

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Hamza Yilmaz

Assignee:

Title:

Semiconductor Device Containing Dielectrically Isolated PN Junction

For Enhanced Breakdown Characteristics

Serial No.:

10/771,593

Filing Date:

02/02/2004

Examiner:

Fetsum Abraham

Group Art Unit:

2826

Docket No.:

YMZ004 US

Confirmation No:

3820

Santa Clara, California August 16, 2005

COMMISSIONER FOR PATENTS P.O. BOX 1450 **ALEXANDRIA, VA 22313-1450** 

## INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, §1.97 and §1.98, Applicant submits for consideration in the above-identified patent application the documents listed on the accompanying Form PTO-1449. The Examiner is requested to make these documents of record.

This Information Disclosure Statement is submitted in conjunction with the accompanying Request for Continued Examination.

Applicant would appreciate the Examiner initialing and returning the Form PTO-1449, indicating that the information has been considered and made of record herein.

Applicant states that each item of information contained in the information disclosure statement was first cited in an International Search Report prepared by the European Patent Office in a counterpart PCT application not more than three months prior to the filing of the information disclosure statement. A copy of the International Search Report is also enclosed.

SILICON VALLEY

Mission College Blvd. Suite 360 Santa Clara, CA 95054 (408) 982-8200 FAX (408) 982-8210

The information contained in this Information Disclosure Statement is to the best of my knowledge and is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

## CERTIFICATE OF MAILING BY "FIRST CLASS"

I hereby certify that this paper or fee is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Commissioner for Patents, P.O. BOX 1450, Alexandria, VA. 22313-1450 on the above date.

David E. Steuber

Respectfully submitted,

David E. Steuber Attorney for Applicants

Reg. No. 25,557

SILICON VALLEY
PATENT GROUP ILP

2350 Mission College Blvd. Suite 360 Santa Clara, CA 95054 (408) 982-8200 FAX (408) 982-8210

U.S. Department of Compete Pate and Trademark Office	Application No.:	10/771,593
	Filing Date:	02/02/2004
( AUG 1 8 2005 (S)	First Named Inventor:	Hamza Yilmaz
\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	Group Art Unit:	2826
INFORMATION DISCLOSURE FINEMENT BY APPLICANT	Examiner Name:	Fetsum Abraham
(Use several sheets if necessary)	Confirmation No.:	3820
	Attorney Docket No.:	YMZ004 US

	-		U.S. Pa	atent Documents				
*Examiner Initials		Document Number	Date	Name	Class	Subclass	App	g Date if
	1.	2004/0084721 A1	05/06/2004	06/2004 Kocon et al. 257 328		328	11/05/2002	
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		Document	Date	Country	Class	Subclass	Yes	No
	2.	EP 1073110 A1	01/31/2001	Europe	21	329		X
	3.	EP 1369927 A2	12/10/2003	Europe	29	78		
	4.	JP 07142713	06/02/1995	Japan	29	78		Х
	5.	JP 08102538	04/16/1996	Japan	29	78		Х
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		<u> </u>	Non Patent 1	Literature Documents				
	6.	Gunta R N et al. A	Novel Planarize	ed Silicon Trench Sidewa	11 Oxide-Merge	d naian Schottk	v (TSO	X-MPS
	6.	Gupta, R.N. et al., A Novel Planarized, Silicon Trench Sidewall Oxide-Merged p-i-n Schottky (TSOX-MPS Rectifier, IEEE Electron Device Letters, Vol. 20, No. 12, December 1999						
	7.	Modules, 2003 IEE	E 34 <sup>th</sup> Annual Po	Demonstration of Silicon wer Electronics Specialist	n Carbide (SiC) its Conference (P	Motor Drive In ESC) Confere	nverter nce	
	-	Proceedings, Acapu	ico, Mexico, 06/1	15/2003				
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Examiner:	Date Considered:					
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if						
not in conformance and not considered. Include copy of this form with your communication with applicant						